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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Conf. No.: 3261

Brian C. Barker, et al.

Serial No.: 09/527,761

Art Unit: 2876

FAX COPY RECEIVED

Filed: March 17, 2000

Examiner: Lee, S.

MAY 3 0 2002

For: WAFER IDENTIFICATION

MARK

Atty Docket: 21806/0085

TECHNOLOGY CENTER 2800

PROPOSED RESPONSE AND AMENDMENT UNDER 37 CFR § 1.111

Commissioner for Patents Washington, D.C. 20231

May 30, 2002

Sir:

In response to the Office Action dated January 30, 2002, the period for response having been extended by one (1) month to May 30, 2002, the following amendments and remarks are submitted in connection with the above-identified application:

## IN THE SPECIFICATION:

Please amend the Specification as follows:

Please replace the paragraph at line 18, page 12 of the Specification with the following replacement paragraph:

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--Similarly, the depth of the pits may depend upon where they are formed. Pits formed on an edge of a semiconductor wafer may be formed a much greater distance into the material of